

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SAWADA ET AL.	
		Examiner Bijan Ahvazi	Art Unit 4171	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0144319 A1	07-2006	Sawada et al.	117/002
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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